

Search Notes

Application/Control No.

10/799,714

Examiner

Jeffrey D. Lane

Applicant(s)/Patent under
Reexamination

MIHASHI ET AL.

Art Unit

2828

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Semiconductor laser with a distance seperating the edge and	6/15/2006	JL
thickness of gold layers	6/26/2006	JL